

AMENDMENTS TO THE SPECIFICATION

Please amend paragraph [0004] as follows:

After fabrication, the mask can be inspected for defects by scanning the surface of the mask and capturing images of the mask with an inspection tool. Defects in the mask are typically identified in a list by their locations. In one embodiment, the mask has an associated grid pattern and the list designates the squares in the grid pattern in which the defects are located. This inspection and defect identification can be performed by specialized equipment/software provided by companies such as KLA-Tencor or Applied Materials.